

(33) ("4551738" | "4954927" | "5081559" | "51845  
 (3643) capacitor with ((sidewall spacer) or sp  
 (3624) (capacitor with ((sidewall spacer) or sp  
 (1128) ((capacitor with ((sidewall spacer) or s  
 (264) (((capacitor with ((sidewall spacer) or s  
 (64) (((((capacitor with ((sidewall spacer) or s  
 (C) (((((capacitor with ((sidewall spacer) or s  
 (47) (((((capacitor with ((sidewall spacer) or s  
 (16) (((((capacitor with ((sidewall spacer) or s  
 (2029) (capacitor with ((sidewall spacer) or s  
 (595) ((capacitor with ((sidewall spacer) or s  
 (271) (((capacitor with ((sidewall spacer) or s  
 (129) (((((capacitor with ((sidewall spacer) or s  
 (91) (((((capacitor with ((sidewall spacer) or s  
 (79) (((((capacitor with ((sidewall spacer) or s  
 (48) (((((capacitor with ((sidewall spacer) or s  
 (111) (((((((capacitor with ((sidewall spacer)  
 (111) (((((((capacitor with ((sidewall spacer)  
 (3643) (capacitor with ((sidewall spacer) or s

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DBS USPAT, US-PGPUB, EPO, JPO, IBM\_TDB

Default operator: OR

Bools

Highlight all hits terms bolded

(((((capacitor with ((sidewall spacer) or spacer)) not (((metal adj insulator adj metal) or (metal-insulator-metal) or "MIM") and (capacitor and ((lower adj electrode) or (bottom adj electrode)) and (sidewall adj spacer))) and channel) and ((titanium adj nitride) or ("TiN")) and ("Ta<sub>2</sub>O<sub>5</sub>" or (tantalum adj pentoxide))) and (plasma)) and (ammonia)

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U	I	P	T	P	Document ID	Issue Date	Pages	Title	Current OR	Current XR	Retrieval	Inventor	S	C	3	4
1	F	P	F	F	US 20020163025	20021107	25	Mixed metal nitride and 257/295 boride barrier layers				Vaartstra, Brian A. et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
2	F	F	F	F	US 20020079523	20020627	25	Reduction of damage in 257/296 semiconductor container				Zheng, Lingyi A. et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
3	F	F	F	F	US 6538274	20030325	19	Reduction of damage in 257/296 semiconductor container	257/296	257/303; 257/306		Zheng, Lingyi A. et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
4	F	F	F	F	US 6445023	20020903	23	Mixed metal nitride and 257/295 boride barrier layers	257/295	257/306; 257/308;		Vaartstra, Brian A. et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
5	F	F	F	F	US 6432835	20020813	59	Process for fabricating 438/720 an integrated circuit	438/720	257/E21.01 1;		Yunogami, Takashi et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
6	F	F	F	F	US 6399399	20020604	26	Method for 438/3 manufacturing	438/3	438/240; 438/253		Yamamoto, Tomoe	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
7	F	F	F	F	US 6218693	20010417	12	Dynamic random access 257/296 memory (DRAM) cell	257/296	257/300; 257/301;		Lu, Chih-Yuan	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
8	F	F	F	F	US 6140179	200007031	13	Method of forming a 438/254 crown capacitor for a	438/254	257/E21.01 2;		Chen, Yinan et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
9	F	F	F	F	US 6136643	20001024	17	Method for fabricating 438/253 capacitor-over-bit-line	438/253	257/E21.01 9;		Jeng, Erik S. et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
10	F	F	F	F	US 6010931	200009104	13	Planarization technique 438/240 for DRAM cell capacitor	438/240	257/E21.64 8;		Sun, Shih-Wei et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
11					US 6002614	19991229	16	Highly dense shape 257/299	257/299	257/306.		Wu, Ching-Tien				

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